



CERTIFICATE OF ACCREDITATION

The ANSI National Accreditation Board

Hereby attests that

NexGen Digital, Inc.

1370 Reynolds Suite 119

Irvine, CA 92614

Fulfills the requirements of

ISO/IEC 17025:2017

and

AS6171 Detection of Suspect/Counterfeit Parts Accreditation Program

In the field of

TESTING

This certificate is valid only when accompanied by a current scope of accreditation document.
The current scope of accreditation can be verified at www.anab.org.

Jason Stine, Vice President

Expiry Date: 17 March 2028

Certificate Number: AT-3475



This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017.
This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory
quality management system (refer to joint ISO-ILAC-IAF Communiqué dated April 2017).

SCOPE OF ACCREDITATION TO ISO/IEC 17025:2017

NexGen Digital, Inc.

1370 Reynolds Suite 119
Irvine, CA 92614

Hande Meissner handem@nexgendigital.com
949 475 8900

TESTING

ISO/IEC 17025 Accreditation Granted: **17 March 2026**

Certificate Number: **AT-3475** Certificate Expiry Date: **17 March 2028**

In recognition of a successful assessment to ISO/IEC 17025:2017 General Requirements for the competence of Testing and Calibration Laboratories, AS6171 General Requirements, and the requirements of the ANAB SR 2429 – Labs Performing Detection of Suspect/Counterfeit Parts Under AS6171 program, accreditation is granted to the **NexGen Digital, Inc.** to perform the following AS6171 slash sheet tests:

Non-Destructive

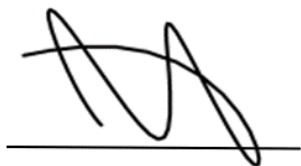
Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
External Visual Inspection	IDEA-STD-1010 AS6081 AS6171/2	Electrical, Electronic and Electromechanical (EEE) Components	Microscope
Mechanical Inspection	IDEA-STD-1010 AS6081 AS6171/2		Microscope, Image Dimension Measuring System, Calipers
X-Ray Inspection	IDEA-STD-1010 AS6081 AS6171/5		X-Ray System
X-Ray Fluorescence (XRF) Inspection	IDEA-STD-1010 AS6081 AS6171/3		XRF System

Mechanical Testing

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Remarking	IDEA-STD-1010 AS6081 AS6171/2	Electrical, Electronic and Electromechanical (EEE) Components	Mineral Spirits, IPA, Microscope
Resistance to Solvents	IDEA-STD-1010 AS6081 AS6171/2		Solvents, Blade, Microscope
Solderability	J-STD-002		Solder Pots, Microscope
Delid/Decapsulation Physical Analysis (DPA)	IDEA-STD-1010 AS6081 AS6171/4		Furnace, Microscope

Electrical

Specific Tests and/or Properties Measured	Specification, Standard, Method, or Test Technique	Items, Materials or Product Tested	Key Equipment or Technology
Electrical Testing	IDEA-STD-1010 AS6081 AS6171/7	Electrical, Electronic and Electromechanical (EEE) Components	DMM, LCR Meter



Jason Stine, Vice President